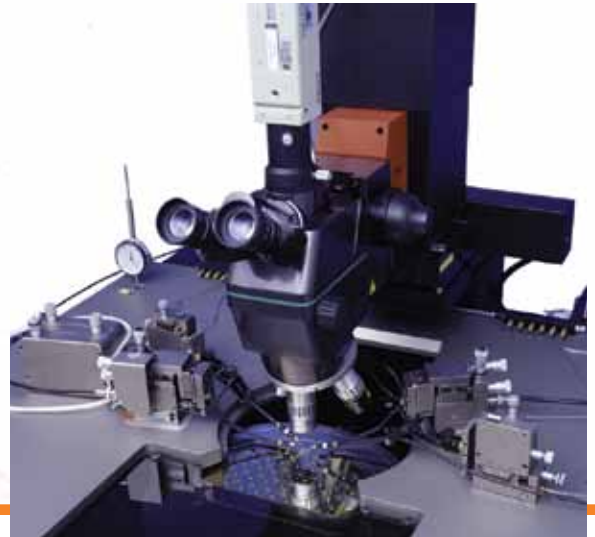


PA300

300 mm Semi-automatic Probe System



DATA SHEET

The PA300 was designed to be most precise and flexible semi-automatic test solution for wafers and substrates up to 300 mm. It is ideal for failure analysis (FA), device characterization and modeling from DC to 500 GHz.

To ensure maximum stability and precision, the PA300 relies on precisely machined components. The use of ground slides and ball-screw drives in closed-loop positioning with glass scales produce excellent performance. Based on your application needs you can choose between vacuum, magnetic, or dedicated high-frequency probe platens.

In order to provide maximum flexibility, our modular design concept allows us to mount microscopes based on your needs. This gives you the freedom to upgrade your PA300 from a simple manual microscope stage to a fully programmable microscope with high magnification.

The PA300 is controlled by our unique ProberBench™ Operating Environment which consists of an independent electronics rack, a joystick controller with integrated color LCD display for full prober control with or without a PC, and a truly flexible PC based graphical user interface (GUI).

To further enhance productivity and ease-of-use, the PM300 can be equipped with a wide range of accessories and upgrades.

FEATURES / BENEFITS

Precision	Highest Z-axis resolution of any production prober Stable, Linux-based controller with optional TTL or GPIB interfaces Manual or motorized holder for backside measurement equipment
Flexibility	Variety of wafer carriers, glass chucks, mechanical edge clamping solutions Wafer-handling robot can be docked onto prober Easy to integrate with ProberBench Operating Environment VisionModule™ available for automated testing processes Interfaces to all major analysis instrumentation, optics software, and testers RF tests supported by wide range of probes and calibration tools, such as calibration substrates and WinCal™ calibration software Smallest footprint
Ease of use	Low cost-of-ownership Fast return on investment Grows with your requirements

SPECIFICATIONS*

Chuck Stage

Travel range in X and Y	300 mm x 300mm
Resolution	0.5 μm
Repeatability	$\pm 1 \mu\text{m}$
Accuracy	$\pm 2 \mu\text{m}$
Planarity	$\pm 15 \mu\text{m}$
Maximum speed	50 mm / sec

Z Movement

Travel range	10 mm
Resolution	0.25 μm
Repeatability	$\pm 1 \mu\text{m}$

Theta Movement

Travel	$\pm 5^\circ$
Resolution	0.0001°

Programmable Microscope Movement (Recommended)

Travel range	50 mm x 50 mm
Resolution	0.25 μm
Repeatability	$\pm 1.0 \mu\text{m}$
Accuracy	$\pm 2.5 \mu\text{m}$
Access lift	130 mm

Manual Platen Movement

Drive type	Handwheel
Contact / separation stroke	0.4 mm
Travel	35 mm

Remote Interfaces

PC	RS232, IEEE488, LAN, TTL, GPIB
Electronics	IEEE488, TTL, GPIB

Utilities

Power	115 / 230 V, 50 / 60 Hz, 600 W (maximum 1500 VA)
Vacuum	Less than 200 mbar abs.
Compressed air	6 ⁻¹⁰ bar

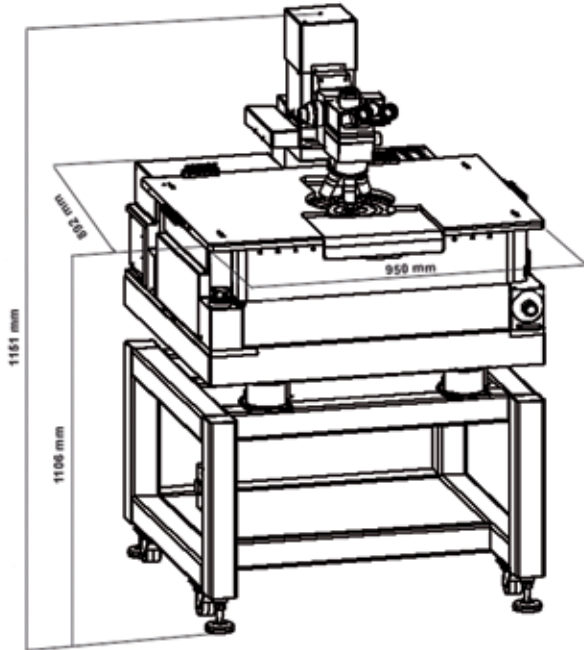
*Data, design and specification depend on individual process conditions and can vary according to equipment configurations.
Not all specifications may be valid simultaneously.

PHYSICAL DIMENSIONS

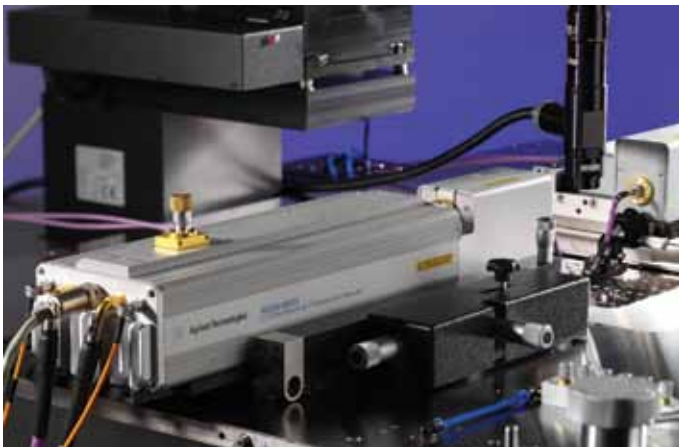
Weight

825 kg

Dimensions



APPLICATIONS



Broadband 110 GHz setup for mm-wave IC measurements.



RF tests with |Z| Probe® on PA300.

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Data subject to change without notice

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